

<b>Notice of References Cited</b>	Application/Control No. 10/630,949		Applicant(s)/Patent Under Reexamination REED ET AL.	
	Examiner Hiep Nguyen		Art Unit 2816	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,342,996	01-2002	Drapkin et al.	361/91.1
*	C	US-6,441,670	08-2002	Coughlin et al.	327/323
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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